



FUKUDA, et al.....Q64291  
PROJECTION ELECTRODE, ITS FORMING METHOD  
AND APPARATUS FOR TESTING AN ELECTRONIC  
COMPONENT  
Filed: April 26, 2001  
Waddell A. Biggart.....202-293-7060  
1 of 12

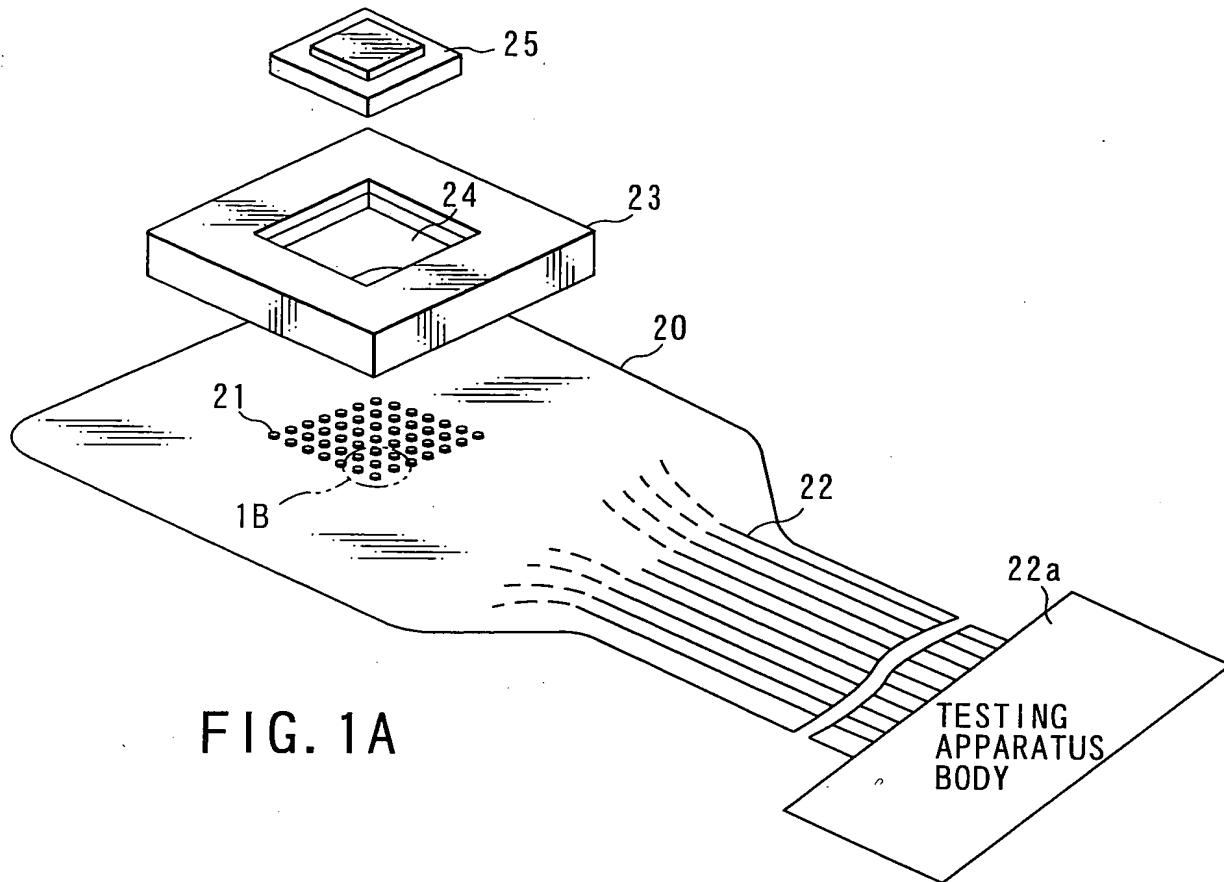


FIG. 1A

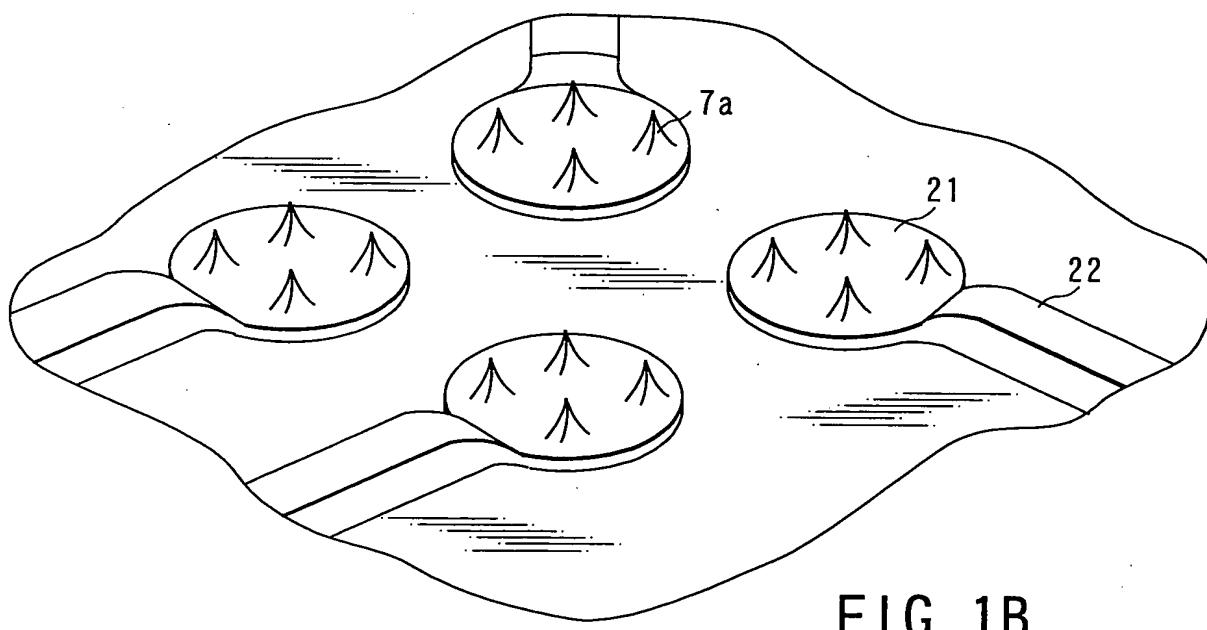
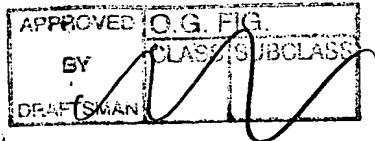


FIG. 1B

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 2 of 12

FIG. 2A

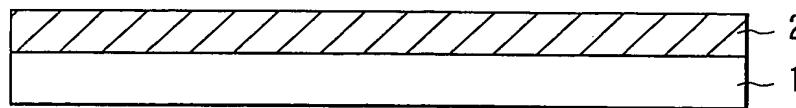


FIG. 2B

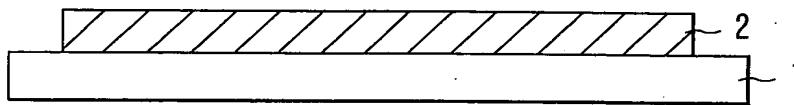


FIG. 2C

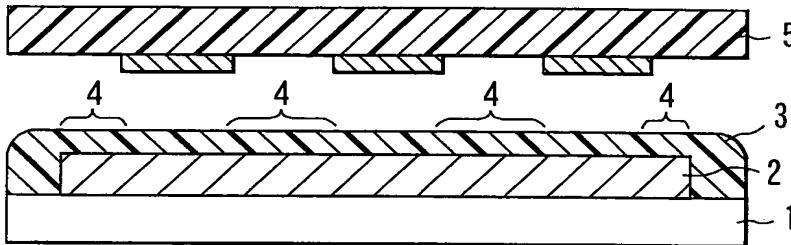


FIG. 2D

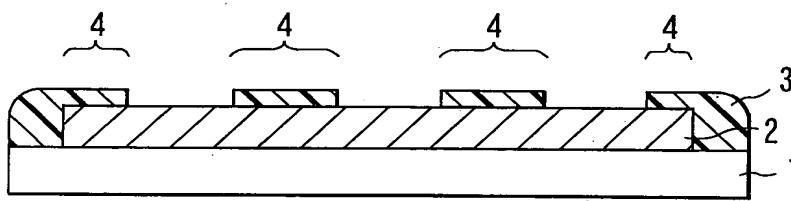


FIG. 2E

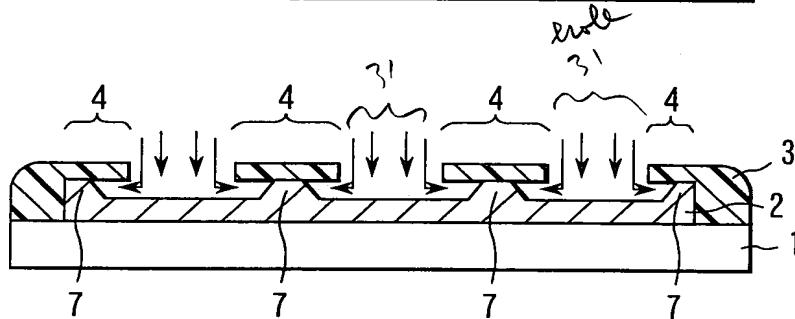


FIG. 2F

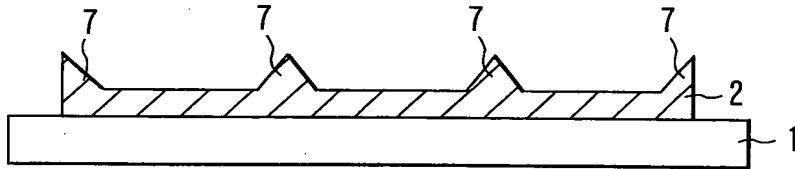
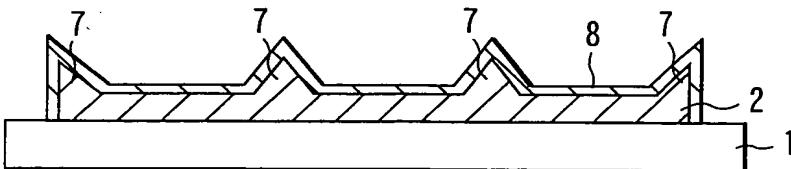
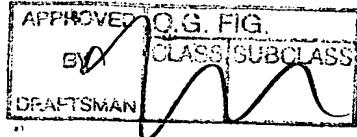


FIG. 2G



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FUKUDA, et al.....Q64291  
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3 of 12

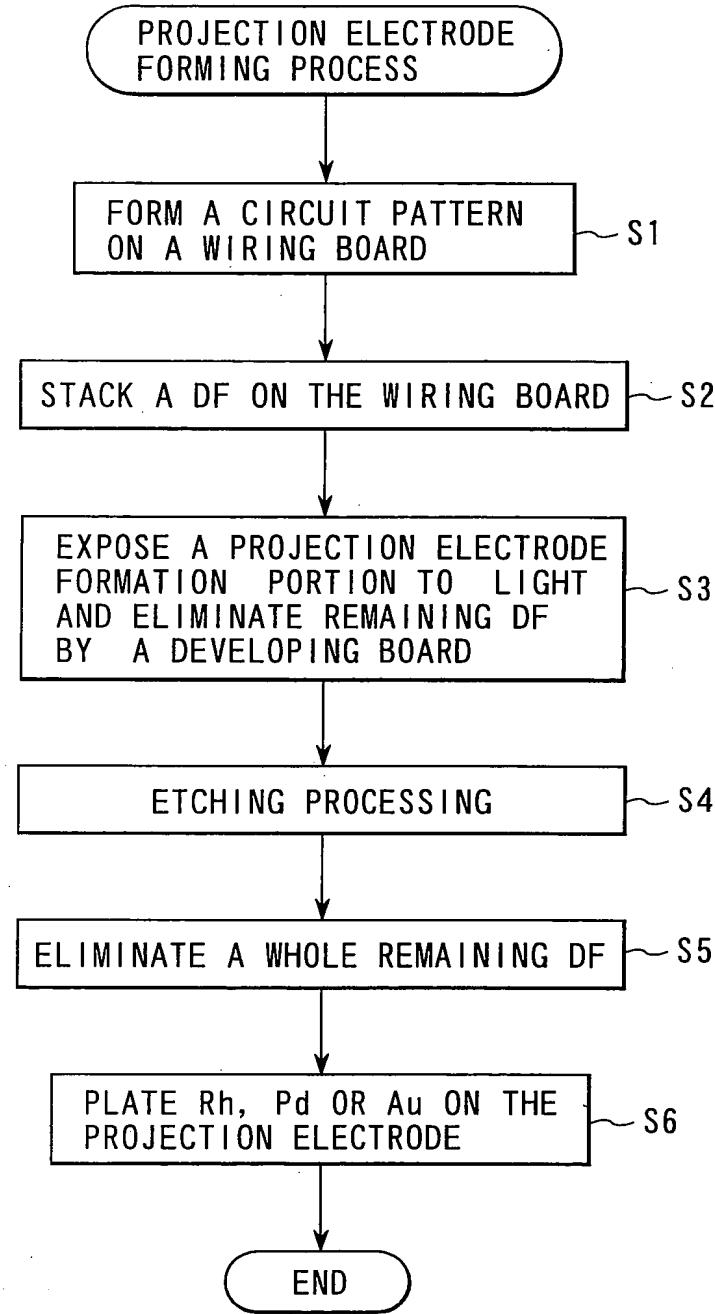


FIG. 3

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APPROVED FOR FIG.  
BY CLASS SUPERVISOR  
DRAFTSMAN

FUKUDA, et al.....Q64291  
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Waddell A. Biggart.....202-293-7060  
4 of 12

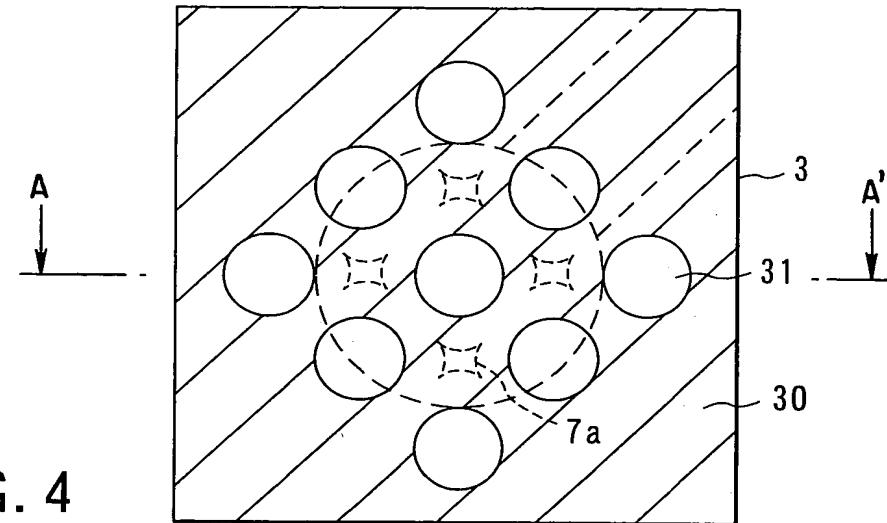


FIG. 4

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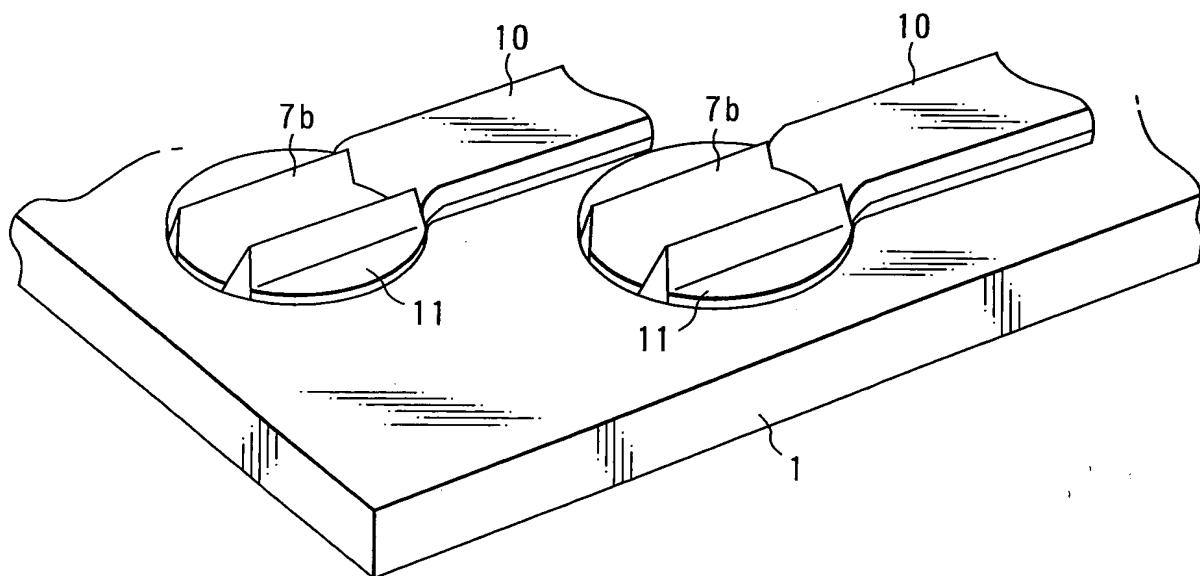
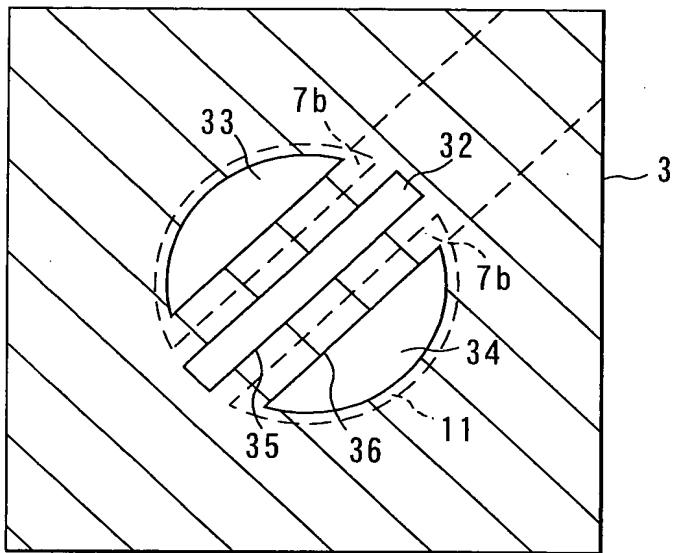


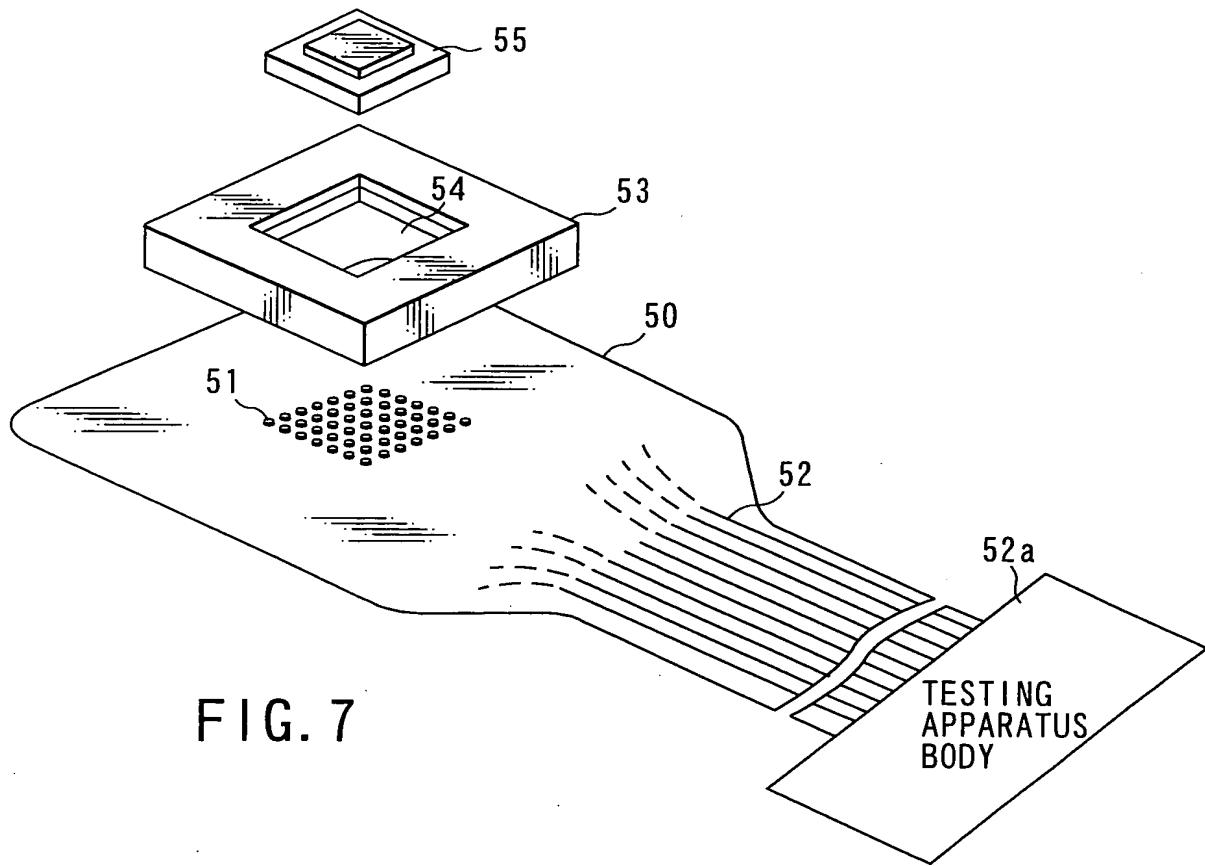
FIG. 5

FIG. 6



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FIG. 7



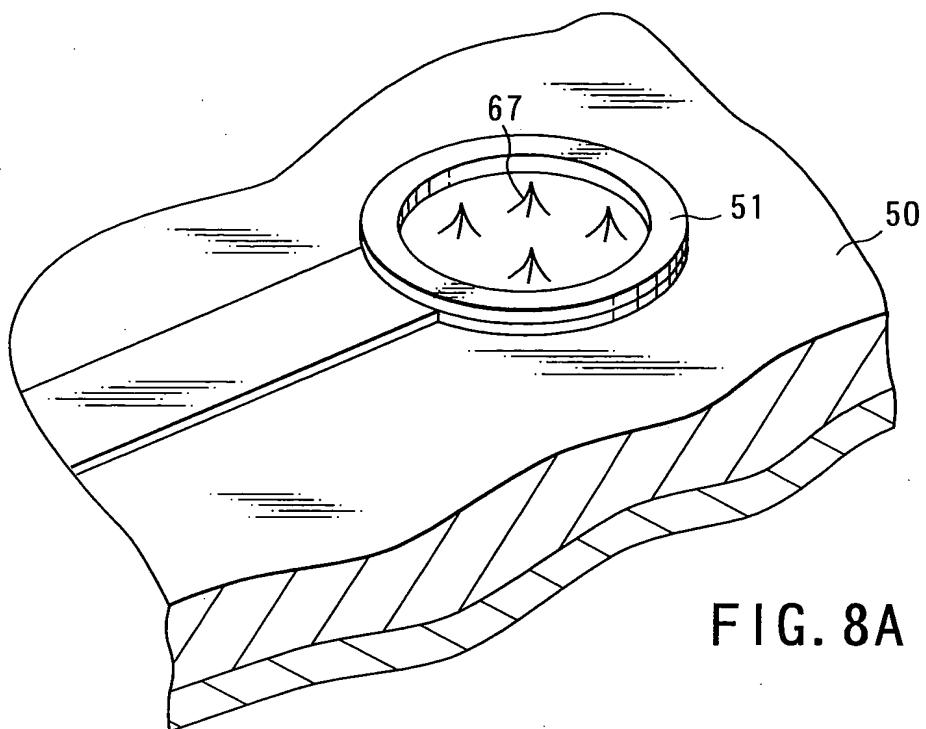


FIG. 8A

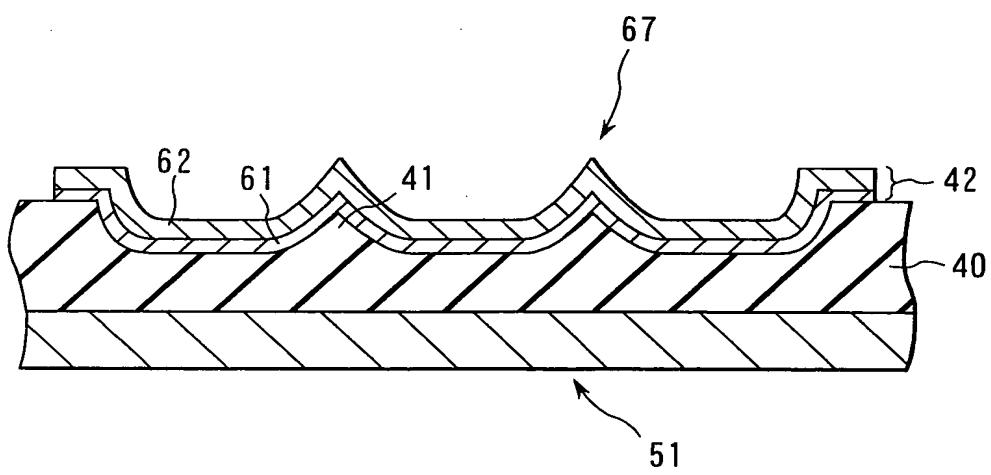


FIG. 8B

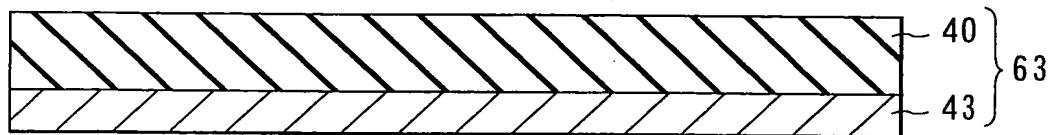


FIG. 9A

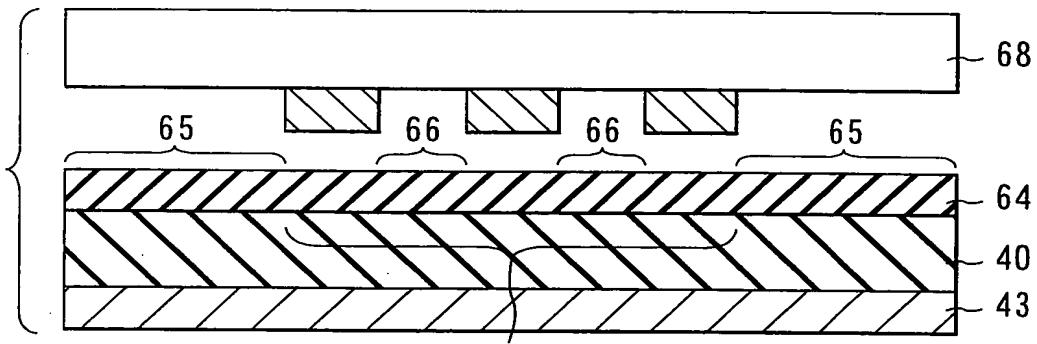


FIG. 9B

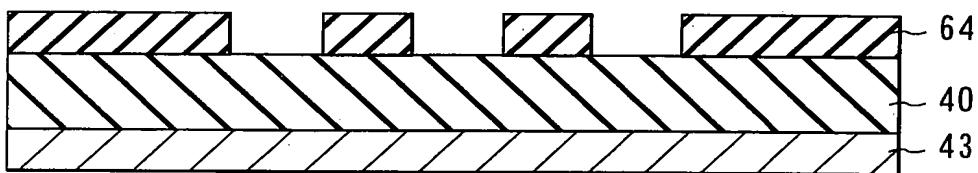


FIG. 9C

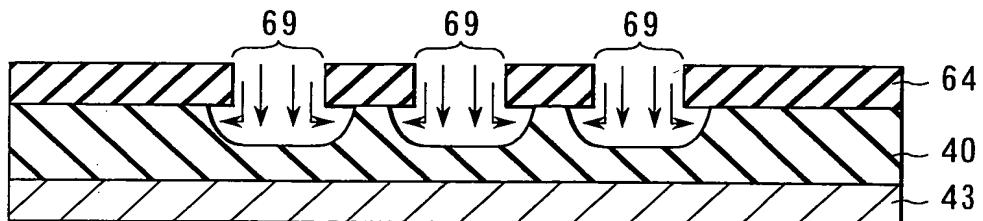


FIG. 9D

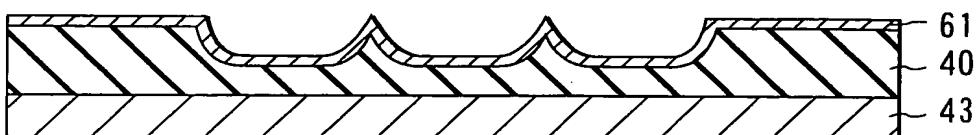


FIG. 9E

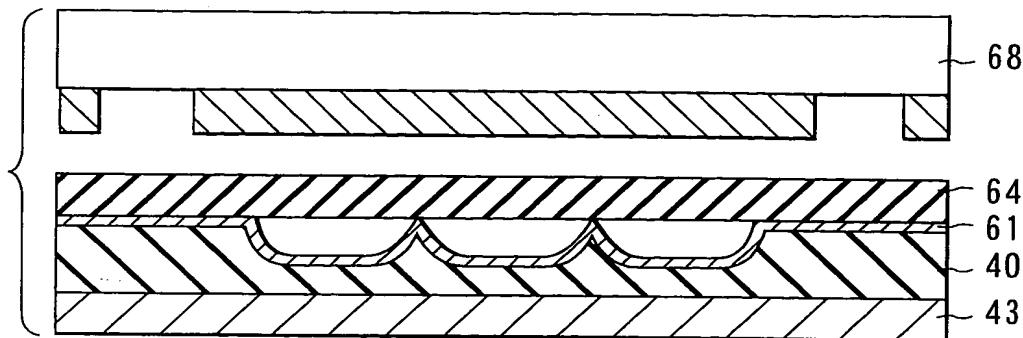


FIG. 9F

FIG. 9G

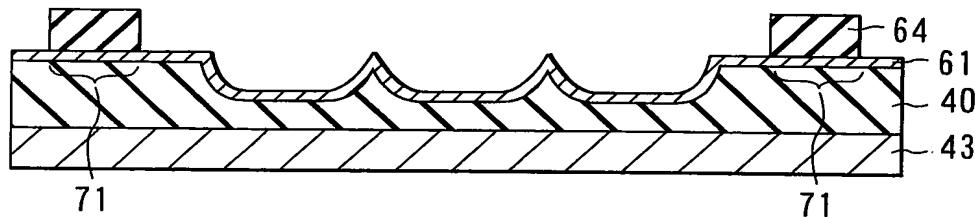


FIG. 9H

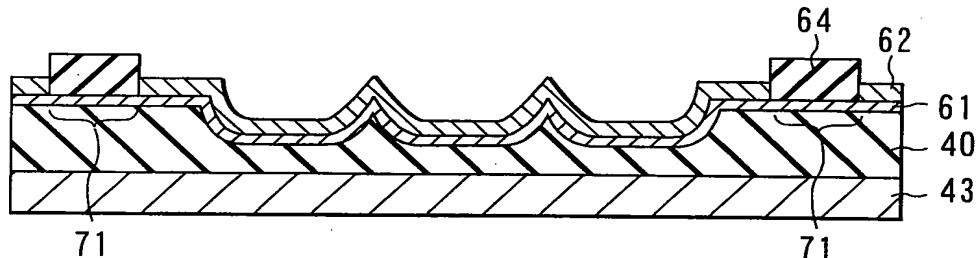


FIG. 9I

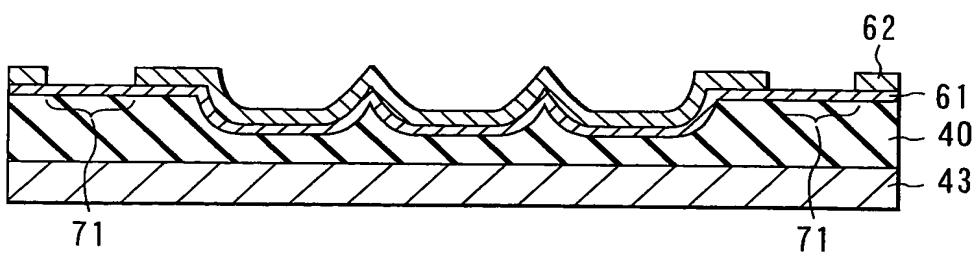
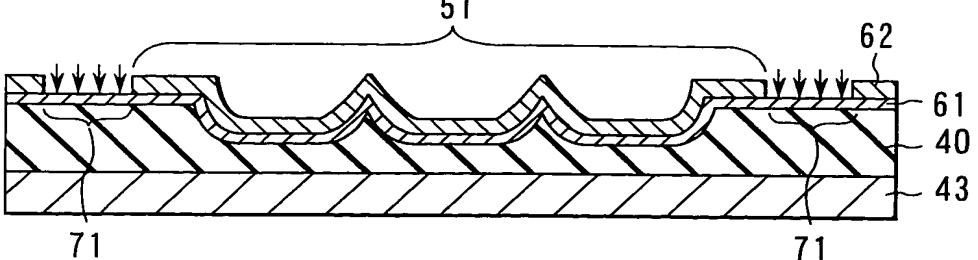


FIG. 9J



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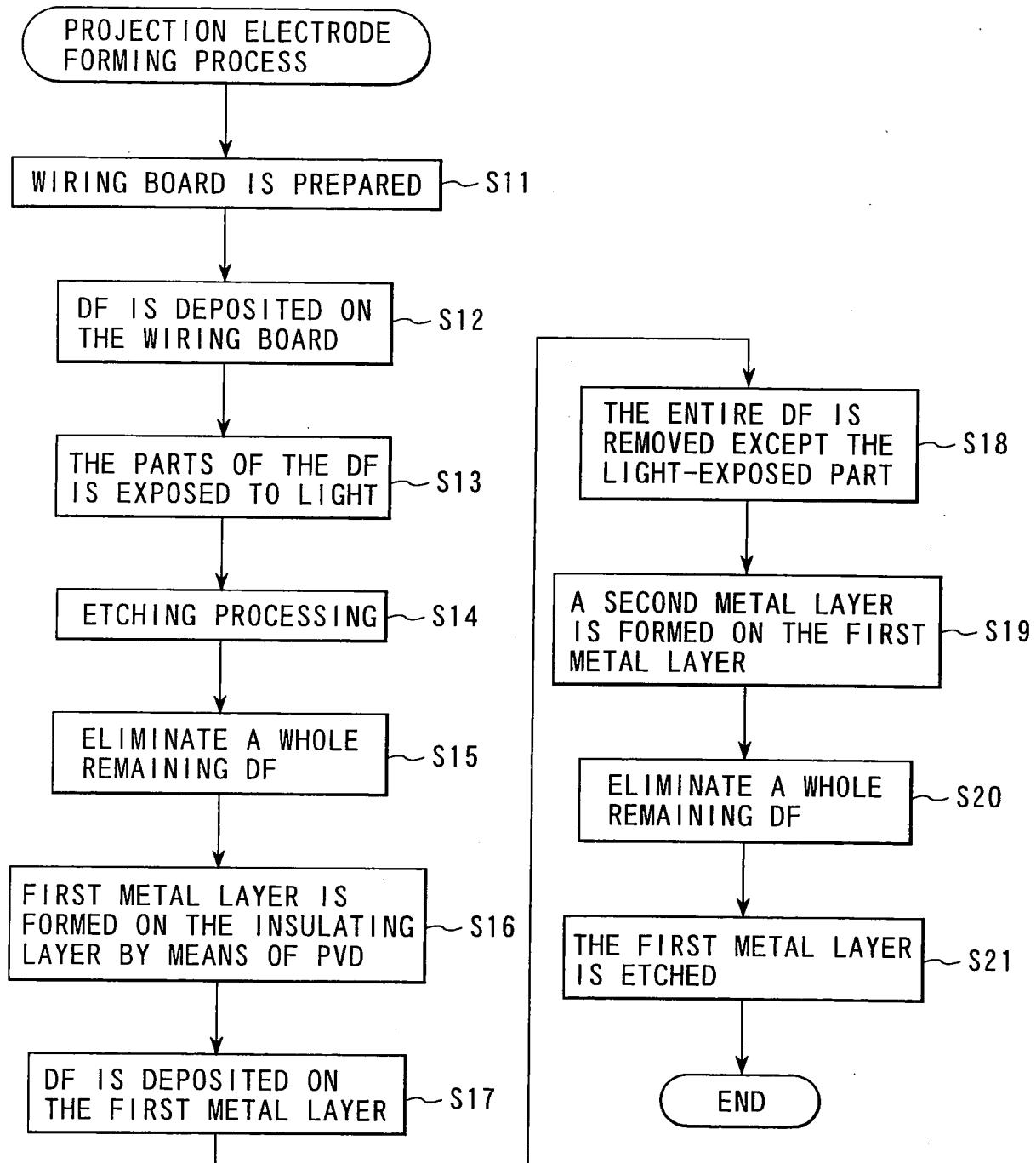


FIG. 10

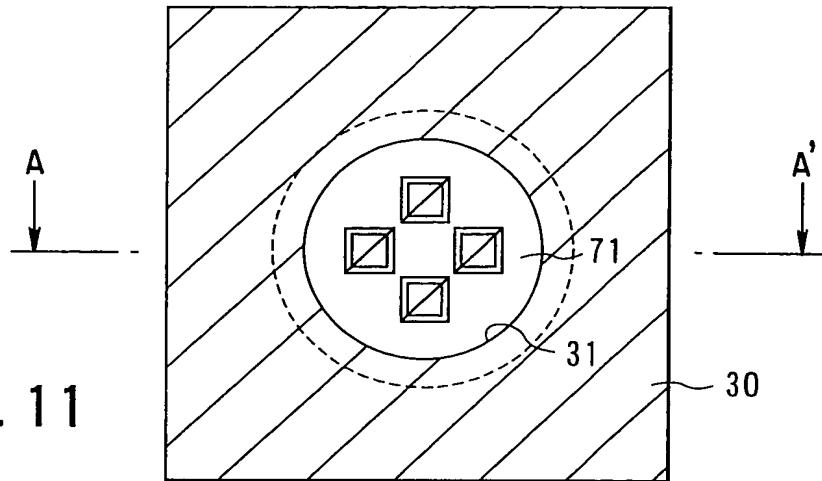


FIG. 11

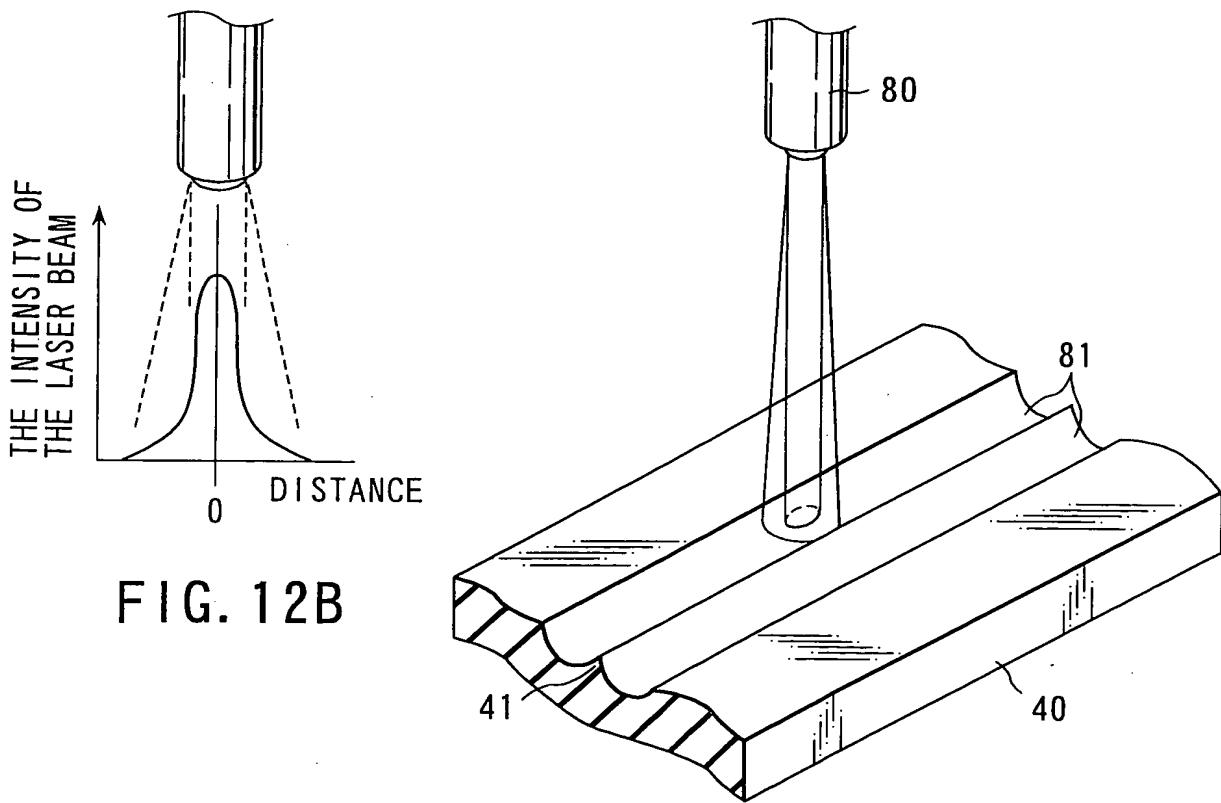


FIG. 12B

FIG. 12A

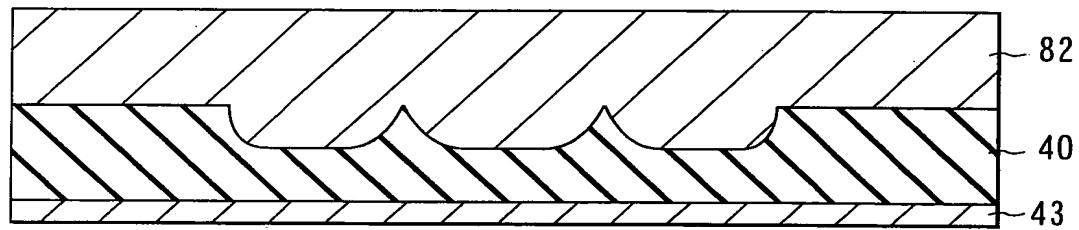
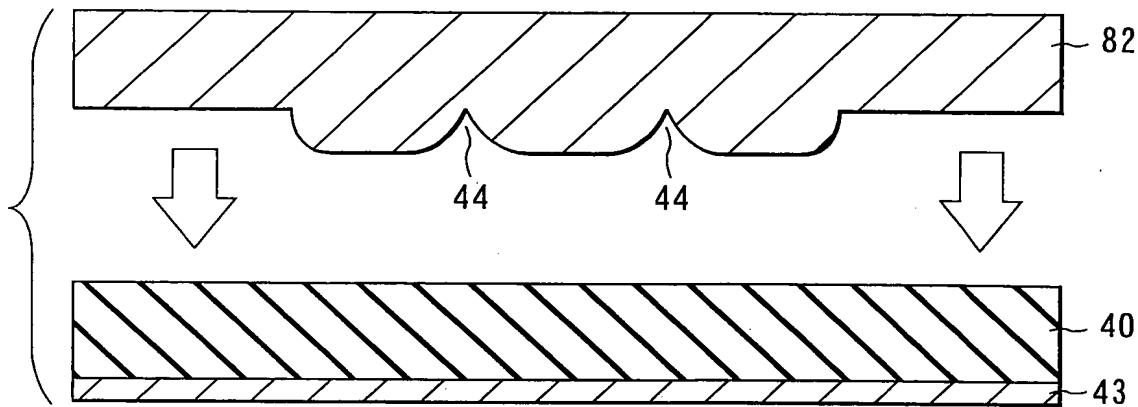


FIG. 13B

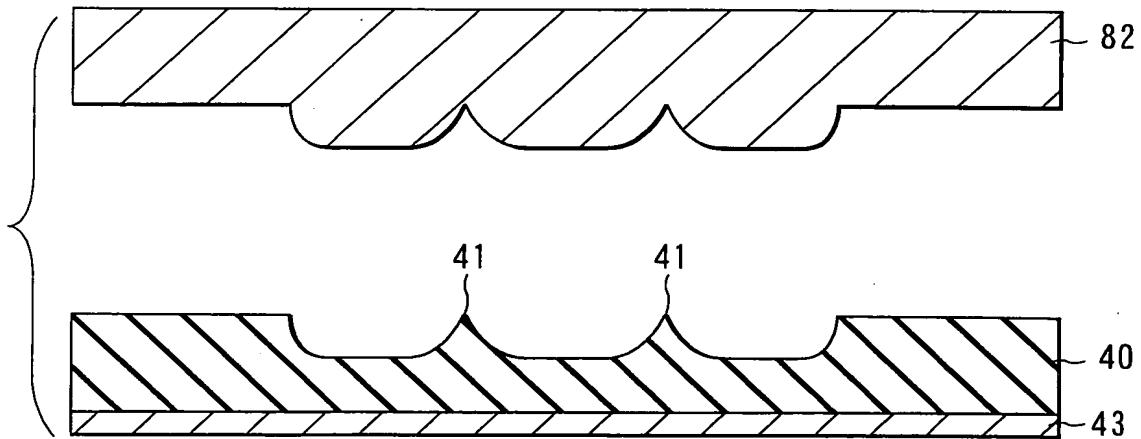


FIG. 13C

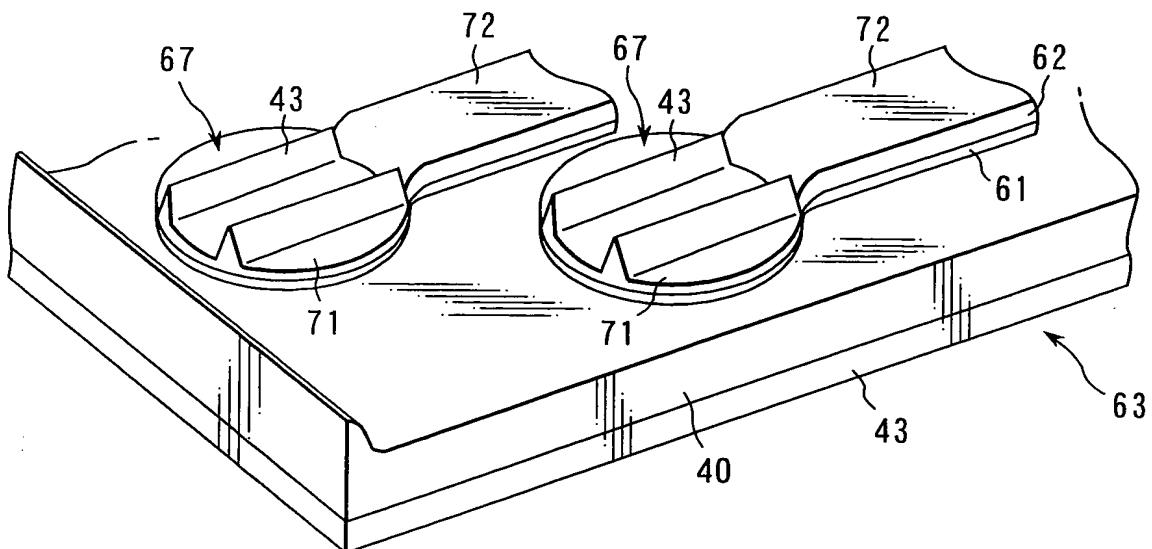


FIG. 14

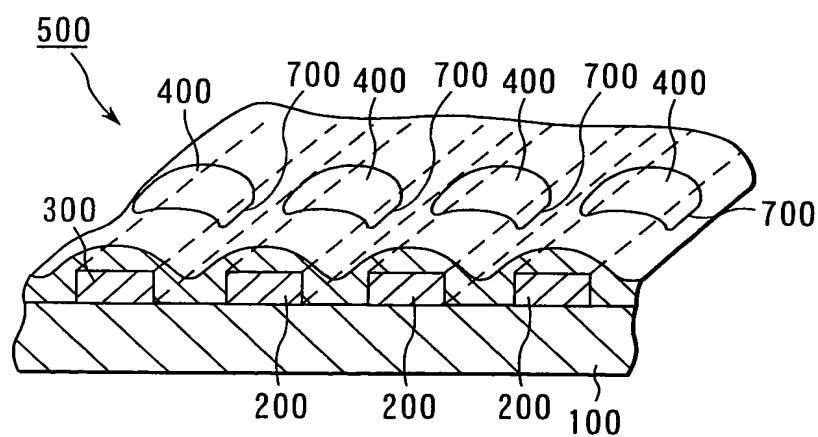


FIG. 15 (PRIOR ART)